

Report No.: SH2201260098

Version : A

闩锁试验报告

Latch up TEST REPORT

委托公司 : 武汉力源半导体有限公司

Company

公司地址 : 上海长宁区天山西路 567 号神州智慧大厦 3 楼

Address

产品名称 : <u>CW32L031</u>

Sample name

委托日期 : 2022 年 1 月 24 日

Date Received

完成日期 : 2022 年 1 月 17 日

Date Tested

实验室认证体系 (TESTING LABORATORY IS APPROVAL BY):

证书编号: IECQ-L DEKRA 17.0004-01

IECQ Certificate of Approval No.: IECQ-L DEKRA 17.0004-01 For Independent

实验室证明事项(WE HEREBY CERTIFY THAT):

对于本报告所载之测试项目及结果,实验室保证由训练合格之专业技术人员负责执行,并忠 实及完整将各项试验结果记录于报告内。

The test(s) shown in the attachment were conducted according to the indicating procedures. We assume full responsibility for the accuracy and completeness of these tests and vouch for the qualifications of all personnel performing them.

	名称 (Name)	签名 (Signature)	日期 (Date)
检测员 Inspector	潘祥仁 Peter Pan	潘祥仁	2022年2月17号
报告审核人 Report reviewer	陈清珑 Larry Chen	渡清 鸐	2022 年 2 月 17 号
报告批准人 Approver	李鹏云 Smile Li	李鹏云	2022 年 2 月 17 号

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This report refers only to the specimen(s) submitted to test, and is invalid if used otherwise

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This report is ONLY valid with the examination seal and signature of this institute.

4. 样品保存自报告签发日起30天。

The tested specimen(s) will only be preserved for thirty days from the date issued, if not collected by the applicant



Report No.: SH2201260098 A Page : 1 of 5

报告内容

TABLE OF CONTENTS

1 讯	息(INFORMATION)	2
1.1	案件讯息(CASE INFORMATION)	2
1.2	试验设备说明(DESCRIPTION OF TEST EQUIPMENT)	2
1.3	环境条件(AMBIENCE CONDITION)	2
1.4	参考文件(REFERENCE DOCUMENT)	2
1.5	测试要求(TEST REQUIREMENT)	2
2 试	验结果(TEST RESULTS)	3
2.1	结果汇整 (SUMMARY)	3
22	测计数据 (TEST DATA)	4

失效分析工程处 (FA Engineering Department)

Report No.: SH2201260098 A Page : 2 of 5

1. 讯息 (INFORMATION)

1.1 案件讯息 (CASE INFORMATION)

试验样品	批次号	封装	数量
Test Sample	LOT NO.	Package	Quantity
CW32L031	NA	LQFP48	3 pcs

1.2 试验设备说明 (DESCRIPTION OF TEST EQUIPMENT)

项目 设备/编号 型号		型号	校准有效期
Items	Equipment/No.	Model	Calibration validity
1	1409189	KEYTEK ZAPMASTER MK2 768	2022年03月23日

1.3 环境条件 (AMBIENCE CONDITION)

标准要求温度 Required temperature	25∵₃ °C	实际温度 Actual temperature	23.3~23.8℃
标准要求相对湿度 Required relative humidity	55± 10 %RH	实际湿度 Actual humidity	51.4~51.9%RH

1.4 参考文件 (REFERENCE DOCUMENT)

项目	依据标准
Items	Standards
1	JESD STANDARD NO.78F JANUARY 2022

1.5 测试要求 (TEST REQUIREMENT)

TRIGGER CURRENT : 100mA~400mA,STEP:100mA(±)

V SUPPLY OVER : 1.25V~2.25V,STEP:1.0V(+)
VOLTAGE TEST 5.25V~8.25V,STEP:1.0V (+)

PULSE DURATION : 10 ms

TEST TEMPERATURE : MAXIMA RATED TEMPERATURE @ 85 °C

SAMPLE QUANTITY : 3 pcs

FAILURE CRITERIA : If absolute Inom is < 25 mA, then absolute Inom + 10mA is used; Or

If absolute Inom is > 25 mA, then > 1.4X absolute Inom is used;

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Report No.: SH2201260098 A Page : 3 of 5

2 试验结果 (TEST RESULTS)

2.1 结果汇整 (SUMMARY)

Trigger Mode	Test Pin	Sample Quantity	Tested Result	V or I Limits	FT Testing Pass Volts	I Iriaaar : Class IIR
	IO5.5V1		PASS +400mA	+8.25V		Temperature Classification: CLASS I
I Trianger (1)	IO5.5V2		PASS +400mA	+8.25V		For Latch-up test at room temperature Class I A :
I Trigger (+)	IO5.5V3		PASS +400mA	+8.25V		Positive I-Test : ≧ 100mA
	IO5.5V4		PASS +400mA	+8.25V		Negative I-Test : \geq 100mA Overvoltage Test : 1.5 x VDD or MSV,
	IO5.5V1		FAIL -400mA	-2.75V		whichever is less Class I B :
1.7.	IO5.5V2	3	FAIL -200mA	-2.75V	PASS	If immunity level A cannot be achieved
I Trigger (-)	IO5.5V3		FAIL -100mA	-2.75V		CLASS II For Latch-up test at maximum-rate
	IO5.5V4		PASS +400mA	-2.75V		ambient temperature Class II A :
	VDD5.5V		PASS +8.25V	+600mA		Positive I-Test : ≥ 100mA
Over Volt Test V _{supply}	VDD1.5V		PASS +2.25V	+600mA		Negative I-Test : ≧ 100mA Overvoltage Test : 1.5 x VDD or MSV, whichever is less Class ⅡB: If immunity level A cannot be achieved

VCAP 外接 1.0UF 电容到地

Group	Pins
GND	8,23,47
VCAP1.5V	1
IO5.5V1	41
IO5.5V2	42
IO5.5V3	43
IO5.5V4	2-7,10-22,25-40,44-46
VDD5.5V	9,24,48

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Report No.: SH2201260098 A Page : 4 of 5

2.2 测试数据 (TEST DATA)

Tested Pins Team	l Trigger (Positive) Sample No. & Failed current (mA)				
rested i ilis realii	#14	#15	#16		
41	PASS +400mA	PASS +400mA	PASS +400mA		
42	PASS +400mA	PASS +400mA	PASS +400mA		
43	PASS +400mA	PASS +400mA	PASS +400mA		
2	PASS +400mA	PASS +400mA	PASS +400mA		
3					
4	PASS +400mA	PASS +400mA	PASS +400mA		
	PASS +400mA PASS +400mA	PASS +400mA PASS +400mA	PASS +400mA PASS +400mA		
5					
<u>6</u> 7	PASS +400mA	PASS +400mA	PASS +400mA		
	PASS +400mA	PASS +400mA	PASS +400mA		
10	PASS +400mA	PASS +400mA	PASS +400mA		
11	PASS +400mA	PASS +400mA	PASS +400mA		
12	PASS +400mA	PASS +400mA	PASS +400mA		
13	PASS +400mA	PASS +400mA	PASS +400mA		
14	PASS +400mA	PASS +400mA	PASS +400mA		
15	PASS +400mA	PASS +400mA	PASS +400mA		
16	PASS +400mA	PASS +400mA	PASS +400mA		
17	PASS +400mA	PASS +400mA	PASS +400mA		
18	PASS +400mA	PASS +400mA	PASS +400mA		
19	PASS +400mA	PASS +400mA	PASS +400mA		
20	PASS +400mA	PASS +400mA	PASS +400mA		
21	PASS +400mA	PASS +400mA	PASS +400mA		
22	PASS +400mA	PASS +400mA	PASS +400mA		
25	PASS +400mA	PASS +400mA	PASS +400mA		
26	PASS +400mA	PASS +400mA	PASS +400mA		
27	PASS +400mA	PASS +400mA	PASS +400mA		
28	PASS +400mA	PASS +400mA	PASS +400mA		
29	PASS +400mA	PASS +400mA	PASS +400mA		
30	PASS +400mA	PASS +400mA	PASS +400mA		
31	PASS +400mA	PASS +400mA	PASS +400mA		
32	PASS +400mA	PASS +400mA	PASS +400mA		
33	PASS +400mA	PASS +400mA	PASS +400mA		
34	PASS +400mA	PASS +400mA	PASS +400mA		
35	PASS +400mA	PASS +400mA	PASS +400mA		
36	PASS +400mA	PASS +400mA	PASS +400mA		
37	PASS +400mA	PASS +400mA	PASS +400mA		
38	PASS +400mA	PASS +400mA	PASS +400mA		
39	PASS +400mA	PASS +400mA	PASS +400mA		
40	PASS +400mA	PASS +400mA	PASS +400mA		
44	PASS +400mA	PASS +400mA	PASS +400mA		
45	PASS +400mA	PASS +400mA	PASS +400mA		
46	PASS +400mA	PASS +400mA	PASS +400mA		



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Report No.: SH2201260098 A

Page : 5 of 5

Tested Pins Team	I Trigger (Negative) Sample No. & Failed current (mA)				
100tou i iiio Teaiii	#14	#15	#16		
41	FAIL -400mA	PASS -400mA	PASS -400mA		
42	FAIL -200mA	FAIL -200mA	FAIL -200mA		
43	FAIL -100mA	FAIL -100mA	FAIL -100mA		
2	PASS -400mA	PASS -400mA	PASS -400mA		
3	PASS -400mA	PASS -400mA	PASS -400mA		
4	PASS -400mA	PASS -400mA	PASS -400mA		
5	PASS -400mA	PASS -400mA	PASS -400mA		
6	PASS -400mA	PASS -400mA	PASS -400mA		
7	PASS -400mA	PASS -400mA	PASS -400mA		
10	PASS -400mA	PASS -400mA	PASS -400mA		
11	PASS -400mA	PASS -400mA	PASS -400mA		
12	PASS -400mA	PASS -400MA	PASS -400mA		
13	PASS -400MA	PASS -400MA	PASS -400mA		
	PASS -400MA	PASS -400MA	PASS -400mA		
14					
15	PASS -400mA	PASS -400mA	PASS -400mA		
16	PASS -400mA	PASS -400mA	PASS -400mA		
17	PASS -400mA	PASS -400mA	PASS -400mA		
18	PASS -400mA	PASS -400mA	PASS -400mA		
19	PASS -400mA	PASS -400mA	PASS -400mA		
20	PASS -400mA	PASS -400mA	PASS -400mA		
21	PASS -400mA	PASS -400mA	PASS -400mA		
22	PASS -400mA	PASS -400mA	PASS -400mA		
25	PASS -400mA	PASS -400mA	PASS -400mA		
26	PASS -400mA	PASS -400mA	PASS -400mA		
27	PASS -400mA	PASS -400mA	PASS -400mA		
28	PASS -400mA	PASS -400mA	PASS -400mA		
29	PASS -400mA	PASS -400mA	PASS -400mA		
30	PASS -400mA	PASS -400mA	PASS -400mA		
31	PASS -400mA	PASS -400mA	PASS -400mA		
32	PASS -400mA	PASS -400mA	PASS -400mA		
33	PASS -400mA	PASS -400mA	PASS -400mA		
34	PASS -400mA	PASS -400mA	PASS -400mA		
35	PASS -400mA	PASS -400mA	PASS -400mA		
36	PASS -400mA	PASS -400mA	PASS -400mA		
37	PASS -400mA	PASS -400mA	PASS -400mA		
38	PASS -400mA	PASS -400mA	PASS -400mA		
39	PASS -400mA	PASS -400mA	PASS -400mA		
40	PASS -400mA	PASS -400mA	PASS -400mA		
44	PASS -400mA	PASS -400mA	PASS -400mA		
45	PASS -400mA	PASS -400mA	PASS -400mA		
46	PASS -400mA	PASS -400mA	PASS -400mA		

No	Over Voltage Test for V _{supply}			
Tested Pins Team	Sample No. & Failed current (mA)			
Testeu Filis Tealii	#14	#15	#16	
9	PASS +8.25V	PASS +8.25V	PASS +8.25V	
24	PASS +8.25V	PASS +8.25V	PASS +8.25V	
48	PASS +8.25V	PASS +8.25V	PASS +8.25V	
1	PASS +2.25V	PASS +2.25V	PASS +2.25V	

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